## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | VOLTOLINA, ELENA | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification	
*	Α	US-6,167,036 A	12-2000	Beven, David Damian Nicholas	370/331	
*	В	US-2002/0061764 A1	05-2002	Kim et al.	455/522	
*	С	US-2003/0021334 A1	01-2003	Levin et al.	375/147	
*	D	US-6,757,544 B2	06-2004	Rangarajan et al.	455/456.1	
*	E	US-5,999,522 A	12-1999	Rohani, Kamyar	370/331	
*	F	US-2003/0125046 A1	07-2003	Riley et al.	455/456	
*	G	US-6,571,097 B1	05-2003	Takai, Kenichi	455/436	
*	н	US-2003/0013443 A1	01-2003	Willars et al.	455/432	
*	1	US-6,292,667 B1	09-2001	Wallentin et al.	455/458	
*	J	US-2002/0151304 A1	10-2002	Hogan, William D.	455/436	
*	К	US-6,594,492 B2	07-2003	Choi et al.	455/436	
	L	US-				
	М	US-				

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s		,			
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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